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Key indicators

Single-crystal X-ray study T = 293 K Mean σ (C–C) = 0.006 Å R factor = 0.060 wR factor = 0.154 Data-to-parameter ratio = 15.8

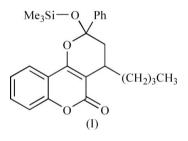
For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

4-Butyl-2-phenyl-2-(trimethylsilyloxy)-3,4-dihydro-2*H*,5*H*-pyrano[3,2-c][1]benzopyran-5-one

In the title compound, $C_{25}H_{30}O_4Si$, the coumarin system is essentially planar and the pyran ring adopts an envelope conformation. There are intramolecular $C-H\cdots O$ interactions and intermolecular π - π stacking interactions in the crystal structure. Received 10 July 2006 Accepted 24 July 2006

Comment

o-Quinone methides constitute a class of highly reactive intermediates and their cycloaddition chemistry has attracted considerable interest (Nair *et al.*, 2001). In our recent research work on the cycloaddition reactions of *o*-quinone methides derived from 4-hydroxycoumarin, we have prepared the title compound, (I), which is obtained from the cycloaddition reaction between coumarin quinone methide and an excess amount of trimethyl[(1-phenylethenyl)oxy]silane. As part of this study, we have undertaken the X-ray crystallographic analysis of (I) in order to elucidate the conformation of this cycloadduct product.



The bond lengths and angles in (I) (Fig. 1 and Table 1) are in good agreement with those found in the related compound 2-methyl-2-(trimethylsilyloxy)-3,4-dihydro-2 H,5*H*-pyrano-[3,2-c][1]benzopyran-5-one (Peng *et al.*, 2005). The coumarin system is essentially planar, with the atom O3 deviating from the mean plane by 0.101 (4) Å. The dihedral angle between the coumarin system and the C11–C16 benzene ring is 46.2 (3)°. The O1/C5–C7/C17/C18 pyran ring adopts an envelope conformation, with atom C6 deviating from the C5/C7/O1/C17/C18 plane by 0.598 (4) Å.

In the crystal structure, the molecular packing is stabilized by intramolecular C-H···O interactions (Table 2) and intermolecular π - π stacking interactions (Table 3).

Experimental

Under argon, a mixture of 4-hydroxycoumarin, 3 equivalents of trimethyl[(1-phenylethenyl)oxy]silane and an excess amount of n-pentanal were suspended in dry dioxane and refluxed for about 20 h. Compound (I) was isolated by column chromatography of the reac-

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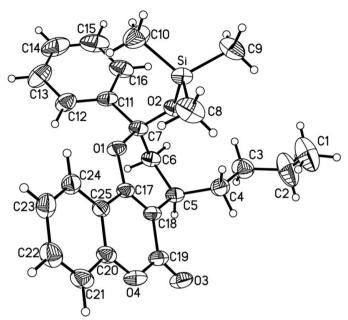


Figure 1

The structure of (I) showing the atom numbering scheme. Displacement ellipsoids are shown at the 30% probability level.

tion mixture on silica gel after evaporation of the solvent, in 65% yield. Single crystals of (I) were obtained by slow evaporation of a petroleum ether-acetone $(1:3 \nu/\nu)$ solution of (I).

Crystal data

 $\begin{array}{l} C_{25}H_{30}O_4\text{Si}\\ M_r = 422.58\\ \text{Monoclinic, }P2_1/n\\ a = 12.138 \ (2) \ \text{\AA}\\ b = 12.874 \ (3) \ \text{\AA}\\ c = 15.300 \ (3) \ \text{\AA}\\ \beta = 90.20 \ (3)^\circ\\ V = 2390.8 \ (8) \ \text{\AA}^3 \end{array}$

Data collection

Enraf-Nonius CAD-4 diffractometer $\omega/2\theta$ scans Absorption correction: ψ scan (XCAD4; Harms & Wocadlo, 1995) $T_{min} = 0.939, T_{max} = 0.966$ 4420 measured reflections

Refinement

Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.060$ $wR(F^2) = 0.154$ S = 1.004208 reflections 266 parameters H-atom parameters constrained Z = 4 $D_x = 1.174 \text{ Mg m}^{-3}$ Mo K α radiation $\mu = 0.13 \text{ mm}^{-1}$ T = 293 (2) K Block, colourless $0.40 \times 0.31 \times 0.28 \text{ mm}$

4208 independent reflections 2484 reflections with $I > 2\sigma(I)$ $R_{int} = 0.078$ $\theta_{max} = 25.0^{\circ}$ 3 standard reflections every 200 reflections intensity decay: none

 $w = 1/[\sigma^{2}(F_{o}^{2}) + (0.0463P)^{2} + 1.79P]$ where $P = (F_{o}^{2} + 2F_{c}^{2})/3$ $(\Delta/\sigma)_{max} < 0.001$ $\Delta\rho_{max} = 0.43 \text{ e} \text{ Å}^{-3}$ $\Delta\rho_{min} = -0.35 \text{ e} \text{ Å}^{-3}$ Extinction correction: *SHELXL97*Extinction coefficient: 0.0192 (13)

Table 1

Selected geometric parameters (Å, °).

02-C7	1.387 (4)	O3-C19	1.205 (4)
02-Si	1.664 (2)	C7-C11	1.532 (4)
C17-O1-C7	119.8 (2)	C20-O4-C19	122.3 (2)
C7-O2-Si	131.0 (2)	C7-C6-C5	114.0 (2)

Table 2

Hydrogen-bond	geometry	(Å,	°).	
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$D - H \cdot \cdot \cdot A$	D-H	$H \cdot \cdot \cdot A$	$D \cdots A$	$D - \mathbf{H} \cdot \cdot \cdot A$
C4-H4A···O2	0.97	2.52	3.064 (4)	115
$C12-H12\cdots O1$	0.93	2.36	2.696 (4)	101

Table 3		
π - π interactions	(Å.	°)

CgI	CgJ	Symmetry code	$Cg \cdots Cg$	Dihedral angle	Interplanar distance	Offset
A	Α	-x, 1-y, 1-z	3.763 (2)	0.0 (2)	3.447 (3)	1.51

CgA denotes the centroid of the aromatic ring C20–C25. The offset is defined as the distance between CgI and the perpendicular projection of CgJ on ring I.

The H atoms were included in the riding-model approximation, with C-H distances of 0.93, 0.96, 0.97 and 0.98 Å for aromatic, methyl, methylene and methine H atoms, respectively, and with $U_{\rm iso}({\rm H}) = 1.2U_{\rm eq}({\rm C})$ or $1.5U_{\rm eq}({\rm methyl} {\rm C})$.

Data collection: *CAD-4 Software* (Enraf–Nonius, 1989); cell refinement: *CAD-4 Software*; data reduction: *XCAD4* (Harms & Wocadlo, 1995); program(s) used to solve structure: *SHELXTL* (Sheldrick, 1997); program(s) used to refine structure: *SHELXTL*; molecular graphics: *SHELXTL*; software used to prepare material for publication: *SHELXTL* and *PLATON* (Spek, 2003).

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